

## Special Issue

# Seismic Data Processing and Imaging

### Message from the Guest Editor

Seismic exploration has long been a cornerstone of subsurface characterization, playing a pivotal role in energy exploration, seismological/geological research, and environmental monitoring. Seismic data processing and imaging are vital components in transforming raw seismic measurements into accurate and interpretable subsurface images. The contributions to this Special Issue will address a wide spectrum of topics, including, but not limited to, seismic data acquisition, noise reduction and denoising techniques, migration algorithms, full waveform inversion, anisotropic media imaging, machine learning applications in seismic imaging, and the integration of various data sources for more accurate subsurface characterization. We invite researchers, scholars, and experts to contribute their original research, case studies, and reviews to provide a comprehensive overview of the state-of-the-art in seismic data processing and imaging. This Special Issue will serve as a platform via which to share their insights, methodologies, and experiences, fostering collaboration and knowledge exchange within the seismic exploration community.

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### Guest Editor

Prof. Dr. Yoshiyuki Kaneda

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### Deadline for manuscript submissions

closed (20 August 2024)



## Applied Sciences

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### Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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### Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo  
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